

# ESDU3121

## 12 V Unidirectional ESD and Surge Protection Device

The ESDU3121 is designed to protect voltage sensitive components from ESD. Excellent clamping capability, low leakage, high peak pulse current handling capability and fast response time provide best in class protection on designs that are exposed to ESD. Because of its small size, it is suited for use in cellular phones, tablets, MP3 players, digital cameras and many other portable applications where board space comes at a premium.

### Features

- Low Clamping Voltage
- Low Leakage
- Small Body Outline: 1.0 mm x 0.6 mm
- Protection for the Following IEC Standards:
  - IEC61000-4-2 Level 4:  $\pm 30$  kV Contact Discharge
  - IEC61000-4-5 (Lightning): 8.5 A (8/20  $\mu$ s)
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

### Typical Applications

- Power Line Protection
- GPIO Protection

Table 1. MAXIMUM RATINGS

Rating		Symbol	Value	Unit
IEC 61000-4-2 (ESD)	Contact		$\pm 30$	kV
	Air		$\pm 30$	
Operating Junction Temperature Range		$T_J$	-65 to + 150	$^{\circ}\text{C}$
Storage Temperature Range		$T_{STG}$	-65 to + 150	$^{\circ}\text{C}$
Minimum Peak Pulse Current		$I_{PP}$	8.5	A

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



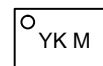
ON Semiconductor®

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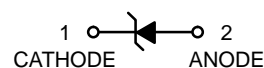


X2DFN2  
CASE 714AB

### MARKING DIAGRAM



YK = Specific Device Code  
M = Date Code



### ORDERING INFORMATION

Device	Package	Shipping†
ESDU3121MXT5G	X2DFN2 (Pb-Free)	8000 / Tape & Reel

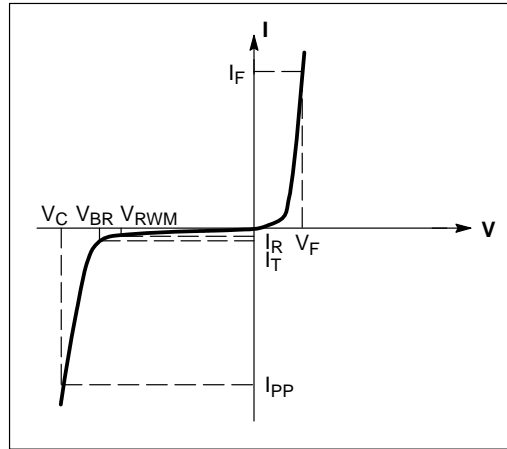
†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

**Table 2. ELECTRICAL CHARACTERISTICS**

( $T_A = 25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter
$I_{PP}$	Maximum Reverse Peak Pulse Current
$V_C$	Clamping Voltage @ $I_{PP}$
$V_{RWM}$	Working Peak Reverse Voltage
$I_R$	Maximum Reverse Leakage Current @ $V_{RWM}$
$V_{BR}$	Breakdown Voltage @ $I_T$
$I_T$	Test Current

\*See Application Note AND8308/D for detailed explanations of datasheet parameters.



**Uni-Directional Surge Protection**

**Table 3. ELECTRICAL CHARACTERISTICS** ( $T_A = 25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Reverse Working Voltage	$V_{RWM}$	I/O Pin to GND			12	V
Breakdown Voltage	$V_{BR}$	$I_T = 1 \text{ mA}$ , I/O Pin to GND	14.1	15	15.8	V
Reverse Leakage Current	$I_R$	@ $V_{RWM}$ , I/O Pin to GND			0.1	$\mu\text{A}$
Reverse Peak Pulse Current	$I_{PP}$	IEC-61000-4-5 (8x20 $\mu\text{s}$ )	8.5			A
Clamping Voltage 8x20 $\mu\text{s}$ Waveform per Figure 3	$V_C$	$I_{PP} = 8.5 \text{ A}$		20.3	22	V
Dynamic Resistance	$R_{DYN}$	I/O Pin to GND, IEC-61000-4-5 (8x20 $\mu\text{s}$ )		0.70		$\Omega$
Junction Capacitance	$C_J$	$V_R = 0 \text{ V}$ , $f = 1 \text{ MHz}$		55		pF

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS

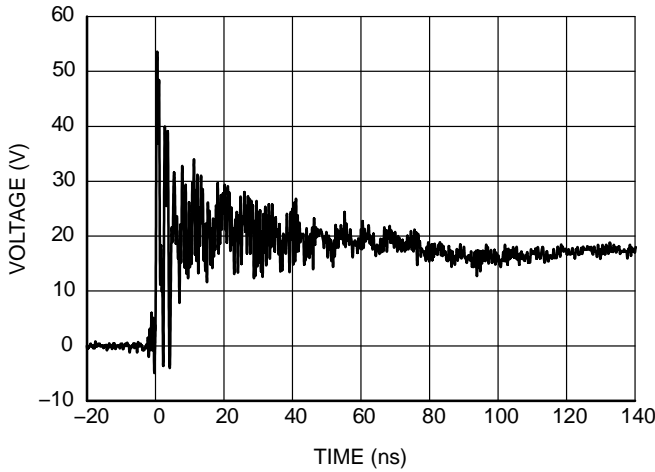


Figure 1. ESD Clamping Voltage Positive 8 kV Contact per IEC61000-4-2

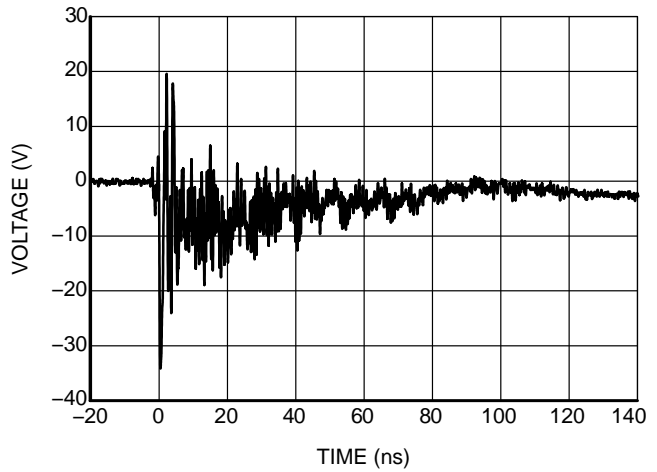


Figure 2. ESD Clamping Voltage Negative 8 kV Contact per IEC61000-4-2

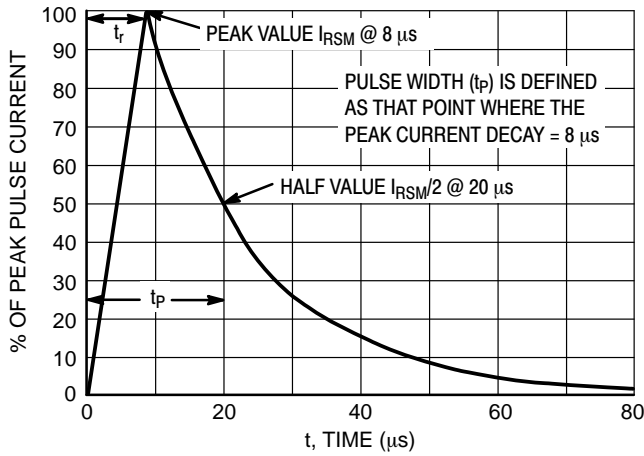


Figure 3. 8 x 20 μs Pulse Waveform

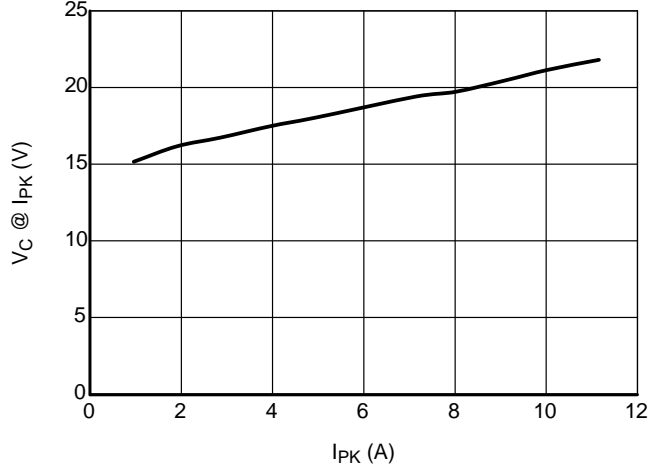


Figure 4. Positive Clamping Voltage vs. Peak Pulse Current ( $t_p = 8/20 \mu s$ )

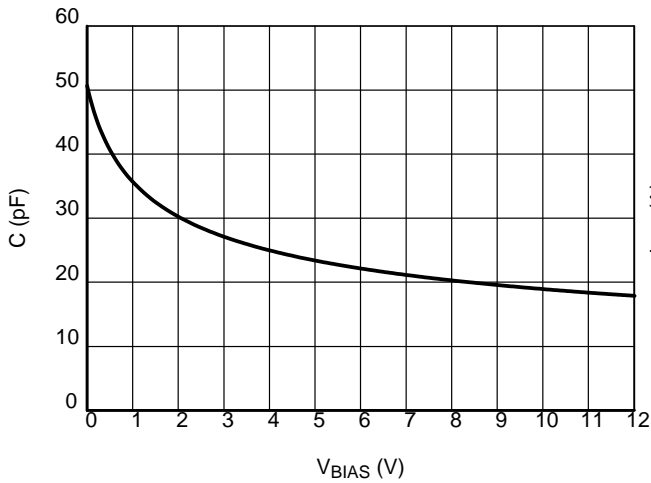


Figure 5. Line Capacitance,  $f = 1 \text{ MHz}$

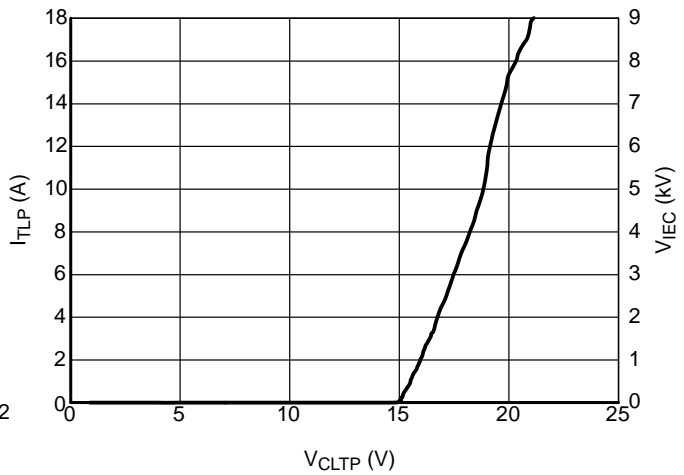
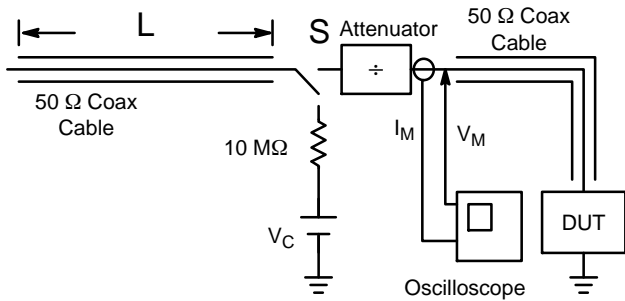


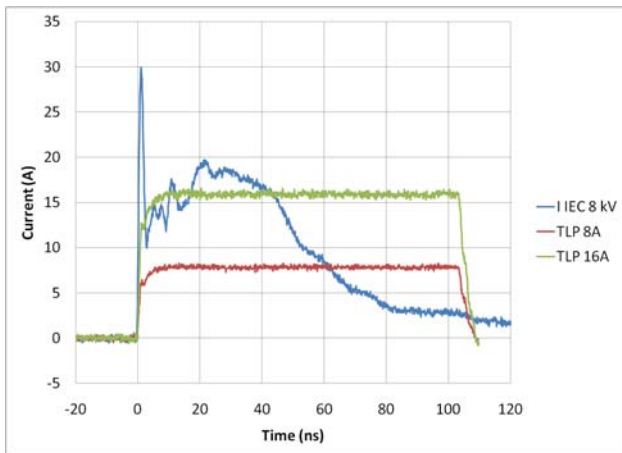
Figure 6. Positive TLP I-V Curve

**Transmission Line Pulse (TLP) Measurement**

Transmission Line Pulse (TLP) provides current versus voltage (I-V) curves in which each data point is obtained from a 100 ns long rectangular pulse from a charged transmission line. A simplified schematic of a typical TLP system is shown in Figure 7. TLP I-V curves of ESD protection devices accurately demonstrate the product’s ESD capability because the 10s of amps current levels and under 100 ns time scale match those of an ESD event. This is illustrated in Figure 8 where an 8 kV IEC 61000-4-2 current waveform is compared with TLP current pulses at 8 A and 16 A. A TLP I-V curve shows the voltage at which the device turns on as well as how well the device clamps voltage over a range of current levels. For more information on TLP measurements and how to interpret them please refer to AND9007/D.



**Figure 7. Simplified Schematic of a Typical TLP System**



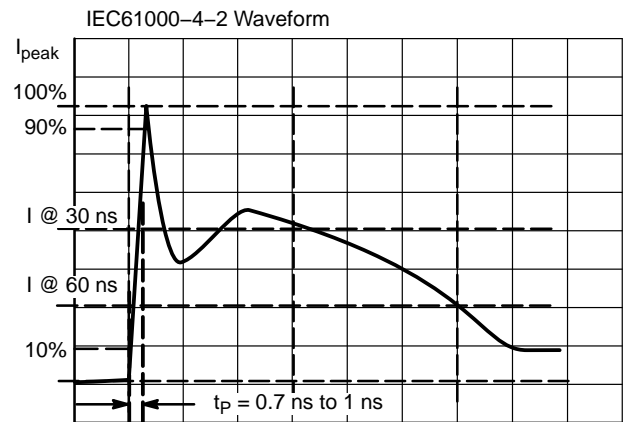
**Figure 8. Comparison Between 8 kV IEC 61000-4-2 and 8 A and 16 A TLP Waveforms**

**ESD Voltage Clamping**

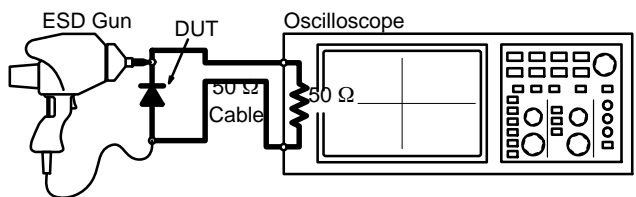
For sensitive circuit elements it is important to limit the voltage that an IC will be exposed to during an ESD event to as low a voltage as possible. The ESD clamping voltage is the voltage drop across the ESD protection diode during an ESD event per the IEC61000-4-2 waveform. Since the IEC61000-4-2 was written as a pass/fail spec for larger systems such as cell phones or laptop computers it is not clearly defined in the spec how to specify a clamping voltage at the device level. ON Semiconductor has developed a way to examine the entire voltage waveform across the ESD protection diode over the time domain of an ESD pulse in the form of an oscilloscope screenshot, which can be found on the datasheets for all ESD protection diodes. For more information on how ON Semiconductor creates these screenshots and how to interpret them please refer to AND8307/D.

**IEC 61000-4-2 Spec.**

Level	Test Voltage (kV)	First Peak Current (A)	Current at 30 ns (A)	Current at 60 ns (A)
1	2	7.5	4	2
2	4	15	8	4
3	6	22.5	12	6
4	8	30	16	8



**Figure 9. IEC61000-4-2 Spec**

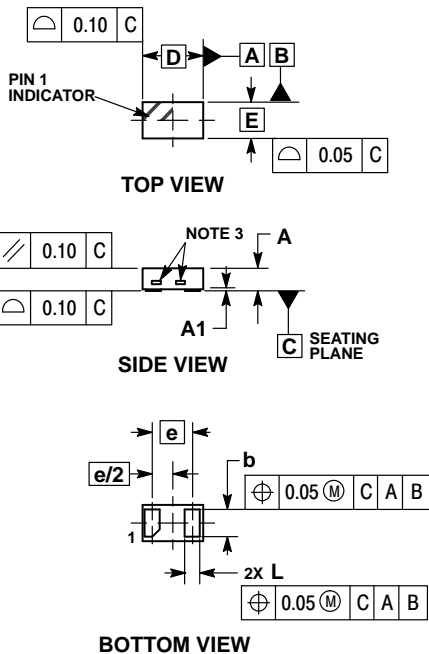


**Figure 10. Diagram of ESD Test Setup**

# ESDU3121

## PACKAGE DIMENSIONS

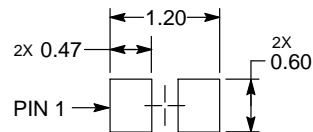
### X2DFN2 1.0x0.6, 0.65P CASE 714AB ISSUE B



- NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: MILLIMETERS.
  3. EXPOSED COPPER ALLOWED AS SHOWN.

MILLIMETERS			
DIM	MIN	NOM	MAX
A	0.34	0.37	0.40
A1	---	0.03	0.05
b	0.45	0.50	0.55
D	0.95	1.00	1.05
E	0.55	0.60	0.65
e	0.65 BSC		
L	0.20	0.25	0.30

### RECOMMENDED SOLDER FOOTPRINT\*



DIMENSIONS: MILLIMETERS

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

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